

Hi-Drop Tester

High speed-multi channel resistance measurement



System feature

- High speed resistance measuring with 1MS/s sampling rate/channel.
- High spec PXI measuring system, up to 64-channel.
- Automatic NG judgement according to JEDEC criteria.
- High accuracy and anti-noise ability.
- Automatically test with currently existing drop tester.
- Measuring the resistance and acceleration above 10000 g combine with accelerometer module.
- Measuring the resistance and strain synchronously combine with strain module.
- Real-time analysis for peak acceleration, velocity and duration.
- Trend analysis for several drop tests.
- Instantaneously data showing, logging, analysis and report generation.

Specifications

Platform	PXI Express
Numbers of Slots	8
Channels	4N ($N \leq 16$), Max. 64 channels
Sampling Rate	Max. 50kS/ch (@16 ch)
Trigger Sampling Rate	Max. 1 MS/Ch
Resistance Measuring Resolution	16 bit
Resistance Measuring Range	20 Ω , 100W, 1kW, 10kW, 100 k Ω , 1M Ω , 10M Ω *note1
Resistance Waveform Logging	Support
Long Time Logging	Support
Measuring Method	Continuous & external trigger acquisition
NG Criteria	Setup independently for each channel
Fail Criteria for each Channel	Flexible (X Drop with Y NG)
Trig Synchronously with Drop Tester	Support
Filter Functions	Low pass, High pass, Band pass
	Cutoff frequency set independently for each channel
Statistical Computing	Support
Virtual Channel	Support
Chart Format	Y-T Graph, X-Y Graph, Bar Chart, Trend
Event Logging	Support
Report Export Format	EXCEL, ASCII
External Trigger Module	High speed photoelectric sensor
High-G Accelerometer (Option)	Support IEPE, Charge or Bridge type accelerometer
	Analysis peak acceleration, speed & duration
	Trend analysis for several drop tests
Auto Drop Altitude Feedback (Option)	Support
Monitor Requirement	1280 \times 768 resolution
Operation System	Windows XP, WIN7, WIN8, WIN10